

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	10/684,520	RYU ET AL.
	<b>Examiner</b>	Art Unit
	Hana A. Sanei	2879

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner